



## Bruker Nano Surface Metrology Workshop

September 20, 2011 10 AM – 4 PM

**University of Washington's NanoTech User Facility**  
Center for Nanotechnology, Fluke Hall, Room 215

Please join us for a day of informative technical presentations and metrology system demonstrations. Space is limited. Sign up early!

RSVP to [Paul.Charell@bruker-nano.com](mailto:Paul.Charell@bruker-nano.com)



### Agenda

**9:30 AM** *Light Eats & Refreshments*

**10 AM to 11:30 AM** — *Welcome & Technical Presentations*

***Self-Optimizing High Resolution Atomic Force Microscopy***

Mayur Savla – Applications Expert, Bruker Nano

***Stylus Profiler Applications Using DektakXT***

Tim Ballinger – Bruker Nano

***3D Optical Microscopy, Beyond the Diffraction Limit of Light***

Mayur Savla – Applications Expert, Bruker Nano

**11:30 AM to Noon** — *System Demonstrations of ContourGT-K1 & DektakXT*

Application scientists from Bruker will demonstrate use and applications of this new instrumentation.

**1 PM to 4 PM** — *Hands-on Sample Analysis with ContourGT-K1 & DektakXT*

Application scientists from Bruker will be available for demonstrations and to provide guidance and training on your samples, time permitting.

\*NOTE - If you would like to bring a sample for analysis please contact Mayur Savla (([Mayur.Savla@Bruker-Nano.com](mailto:Mayur.Savla@Bruker-Nano.com))) to discuss and schedule a time.



To RSVP contact Bruker at [Paul.Charell@bruker-nano.com](mailto:Paul.Charell@bruker-nano.com)